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Type: **Poster**

## Analysing Cu electrodes with AFM and SEM

*Tuesday, 20 September 2022 17:30 (10 minutes)*

In this work Cu electrodes were characterized with AFM and SEM. The AFM topology map was used to create a field enhancement map of the surface. SEM images show different structures with multi-scale roughness. A hypothesis for CuO protrusion growth on the Cu electrodes is introduced.

### Topic

Experiments and Diagnostics

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**Session Classification:** Poster Session

**Track Classification:** Experiments